EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	2105	382/144-150.ccls.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/05/18 09:11
L2	3575	382/141-150.ccls.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/05/18 09:11
L3	18	382/141-150.ccls. and (threshold near2 region) with defect	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/05/18 09:28
L4	17	382/141-150.ccls. and (threshold) with defect with upper with lower	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/05/18 09:40
L5	2	("20040150813").PN.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/05/18 10:54
L6	260	automatic adj defect adj classification	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/05/18 10:55
L7	84	automatic adj defect adj classification and monitor	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/05/18 11:09

EAST Search History

L8	22268	illuminating adj light	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/05/18 11:09
L9	264	illuminating adj light with ultra\$violet	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/05/18 11:09

5/18/07 12:58:37 PM
C:\Documents and Settings\drosariovasquez\My Documents\EAST\Workspaces\10749670\search.wsp Page 2

9	m
re	RELEASE 2.3
	RELEA
X	
H	
П	

Home | Login | Logout | Access Information | Alerts | Sitemap | Help

Welcome United States Patent and Trademark Office

.□Search Results	BROWSE	SEARCH	IEEE XPLORE GUIDE	SUPPORT
Results for "(((inspection <near> wafer<in>metadata))<and>(threshold*<in>metadata))" Your search matched 13 of 322 documents. A maximum of 100 results are displayed, 25 to a page, sorted by Relevance in Descending order.</in></and></in></near>	and>(threshold* <in> ted by Relevance in I</in>	metadata))" Descending order.		⊠e-mail 🚍 printer triendby
•	•			

» Search Options	ptions	Mod	Modify Search	
View Session History	on History	((ins	(((inspection <near> wafer<in>metadata))<and>(threshold*<in>metadata))</in></and></in></near>	
New Search	뒤			
» Key		Disp	Display Format: © Citation C Citation & Abstract	
IEEE JNL	IEEE Joumal or Magazine	vie	view selected items Select All Deselect All	
IET JNL	IET Joumal or Magazine	•		
IEEE CNF	IEEE Conference Proceeding		1. CASTAM: A process variation analysis simulator for MOS LSI's Aoki, Y.: Toyabe, T.: Asai, S.; Haqiwara, T.;	
IET CNF	IET Conference Proceeding		Electron Devices, IEEE Transactions on Volume 31, Issue 10, Oct 1984 Page(s):1462 - 1467	
IEEE STD	IEEE Standard		AbstractPlus Full Text: PDF(672 KB) IEEE JNL Rights and Permissions	
			2. Robustness evaluation of cost-optimum sampling plan for in-line wafer inspection by using Taggeti methods	ection by
			Suzuki, R.; Nakamae, K.; Fujioka, H.;	
			Semiconductor Manutacturing, 2005, ISSM 2005, IEEE International Symposium on 13-15 Sept. 2005 Page(s):386 - 389	5
			Digital Object Identifier 10.1109/ISSM.2005.1513385	
			AbstractPlus Full Text: PDF(322 KB) IEEE CNF Rights and Permissions	
			 Monitoring and preventing arc-induced wafer damage in 300mm manufacturing Parker, J.; Reath, M.; Krauss, A.F.; Campbell, W.J.; Integrated Circuit Design and Technology, 2004. ICICDT '04. International Conference on 2004 Page(s):131 - 134 	ing ence on
			Digital Object Identifier 10.1109/ICICDT.2004.1309927	

AbstractPlus | Full Text: PDF(441 KB) | IEEE CNF

___ PALM INTRANET

Day: Friday Date: 5/18/2007 Time: 09:59:03

Content Information for 10/749670

Search Another: Application# Search or Patent# Search PCT / Search or PG PUBS # Search Attorney Docket # Search						
Bar	· Code #		Search			
Appln Info Co	ontents 🗜 🖰	etition Info	Ally/Agendino (emindly/Reexam From Pale)			
Date	Status	Code	Description			
04/09/2007		DOCK	CASE DOCKETED TO EXAMINER IN GAU			
03/21/2006		DOCK	CASE DOCKETED TO EXAMINER IN GAU			
02/22/2006		C.ADB	CORRESPONDENCE ADDRESS CHANGE			
09/21/2005		M844	INFORMATION DISCLOSURE STATEMENT (IDS) FILED			
09/21/2005		WIDS	INFORMATION DISCLOSURE STATEMENT (IDS) FILED			
07/15/2005		DOCK	CASE DOCKETED TO EXAMINER IN GAU			
06/13/2005		C.ADB	CORRESPONDENCE ADDRESS CHANGE			
03/18/2005		LET.	MISCELLANEOUS INCOMING LETTER			
03/18/2005		M844	INFORMATION DISCLOSURE STATEMENT (IDS) FILED			
03/18/2005		WIDS	INFORMATION DISCLOSURE STATEMENT (IDS) FILED			
08/26/2004		TSSCOMP	IFW TSS PROCESSING BY TECH CENTER COMPLETE			
12/30/2003		RQPR	REQUEST FOR FOREIGN PRIORITY (PRIORITY PAPERS MAY BE INCLU			
08/25/2004	30	DOCK	CASE DOCKETED TO EXAMINER IN GAU			
06/18/2004		TI1050	TRANSFER INQUIRY TO GAU			
04/30/2004	20	WROIPE	APPLICATION RETURN FROM OIPE			
04/30/2004	18	ROIPE	APPLICATION RETURN TO OIPE			
04/29/2004	20	OIPE	APPLICATION DISPATCHED FROM OIPE			
04/20/2004		COMP	A DDI ICATION IS NOW COMPLETE			

Appin Info Contents Pet	ition Info	Info : Continuity/Reexa	im Foreign Data
-------------------------	------------	-------------------------	-----------------

CASE CLASSIFIED BY OIPE

IFW SCAN & PACR AUTO SECURITY REVIEW

CLEARED BY OIPE CSR

INITIAL EXAM TEAM NN

To go back use Back button on your browser toolbar.

02/26/2004

02/26/2004

01/24/2004

12/30/2003

Back to PALM | ASSIGNMENT | OASIS | Home page

19

CLSS

L194

SCAN

IEXX